Fabrication of perpendicular magnetized spin filter junctions

Hokkaido Univ, [°]Hiroki Kajita, Takashi Yanase, Taro Nagahama, Toshihiro Shimada

E-mail: tjuvolley0@ec.hokudai.ac.jp

[Introduce]

The spin filter effect is the effect that spin-polarized current is generated due to exchange splitting in the magnetic tunnel barrier. Although, perpendicular magnetic tunnel barrier will enable the perpendicular spin filter junction, it has not been realized yet. In this study, we fabricated FePt and $CoFe_2O_4$ epitaxial films for perpendicular magnetized spin filter device. FePt films are very popular as perpendicular magnetization films. For $CoFe_2O_4$, the perpendicular magnetic anisotropy can be induced by lattice strain[1]. $CoFe_2O_4$ is the ferromagnetic insulator with high Curie temperature, so that the room temperature operation of spin filter devices is expected.

[Experiment]

L1₀-FePt and CoFe₂O₄ thin films were prepared on MgO(100) substrate by MBE method. Sample structures were MgO(100)/Cr(30 nm)/Pt(20 nm)/[Fe/Pt]₁₀(3.4 nm)/Fe(t_{Fe}=0-1.5 nm)/MgO(2 nm) and MgO(100)/MgO(20 nm)/ CoFe₂O₄ (3-5 nm)/Al₂O₃(3 nm). FePt films were prepared by alternating deposition of Fe and Pt monatomic layers at 500°C. Then Fe layers were deposited in wedge shape using linear shutter at RT and annealed at 300°C. CoFe₂O₄ thin films were grown at 300°C in the oxygen atmosphere of 4×10^{-4} Pa and annealed at various temperatures. The epitaxial growth and surface structures were observed by RHEED and AFM. The magnetic properties were measured by MOKE at RT.

Result

Fig.1 shows MOKE loops of FePt/Fe (t_{Fe}) layers for various thickness of Fe layer. The magnetic field was applied perpendicular to the film plane. The films showed clear perpendicular magnetic anisotropy. The coercivity decreased with increasing t_{Fe} monotonically. The Hc at t_{Fe} =1.5 nm was half as large as Hc for t_{Fe} =0 nm. Fig.2 shows the RHEED pattern of CoFe₂O₄ annealed at 600°C. The clear streak pattern was observed. The surface roughness R_a of CoFe₂O₄ was estimated as 0.28 nm from the AFM measurements.



for various thickness of Fe layer.

[1] Huang et al. Appl. Phys. Lett. 89, 262506 (2006)



Fig.2. The RHEED pattern of $CoFe_2O_4$ annealed at 600°C.